

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/648,018	FUJIUNE ET AL.	
Examiner	Art Unit	
Adam R. Giesv	2627	

	SEAR	CHED	
Class	Subclass	Date	Examiner

FERFERENCE SEARCHED		
Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Consulted Wayne Young on prior art search	5/22/2006	ARG		
Consulted THang Tran on prior art search	5/22/2006	ARG		
Consulted Jorge Ortiz-Criado on prior art search	5/22/2006	ARG		
EAST search included	5/24/2006	ARG		